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The use of electron optical methods to determine the crystal structure of a
modulated phyllosilicate: Parsettensite

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For deposit: Table 3

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Table 3. Calculated and observed superlattice reflections* for parsettensite based on model coordinates for input to the Fourier analysis. Final R = 19.81%.

h	k	F _o	F _c	ΔF
2	0	22	16	7
3	1	-150	-150	8
4	0	44	58	-13
4	2	44	62	-18
5	1	44	62	-18
5	3	-40	-40	1
6	0	-36	-2	-34
6	2	-102	-97	-5
6	4	63	78	-15
7	1	-40	-39	0
7	3	-93	-85	-8
7	5	22	23	-1
8	0	-36	-54	17
8	2	-93	-84	-10
8	4	-60	-44	-16
8	6	70	60	10
9	1	63	79	-16
9	3	-59	-62	3
9	5	-25	-27	2
9	7	75	55	20
10	0	-31	-39	8
10	2	-60	-43	-17
10	4	49	65	-16
10	6	-29	-24	-5
10	8	-26	-25	-1
11	1	22	23	-1
11	3	49	64	-15
11	5	-34	-32	-2
11	7	-31	-43	11
11	9	2	0	2
12	0	-54	-45	-9
12	2	-25	-26	2
12	4	-31	-30	-2
12	6	36	28	8
13	1	70	60	10
13	3	-34	-32	-2
13	5	-31	-25	-7
14	0	56	73	-17
14	2	-29	-23	-6
14	4	-31	-25	-7
15	1	75	55	20

15	3	36	28	8
15	5	1	0	1
16	0	89	114	-25
16	2	-31	-43	12
17	1	-26	-25	-1
18	0	1	0	1

* Only the non-redundant reflections within a 60° section of the basal plane are provided. Generation of additional data may be derived by reflection and rotation according to:

$$h(nref+1)=(h(nref)-3*k(nref))/2$$
$$k(nref+1)=(h(nref)+k(nref))/2$$

where nref is the reflection counter. Thus, nref is a given reflection in the table and nref+1 is the additional data.
